

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10598934	NAKAHATA ET AL.
	Examiner	Art Unit
	SELIM AHMED	2826

SEARCHED

Class	Subclass	Date	Examiner
257	13, 103	12/13/08	/sa/
438	46, 483, 481	12/13/08	/sa/

SEARCH NOTES

Search Notes	Date	Examiner
Text search such as, Group III, III-V, nitride, GaN, GaInN, GaAIN, InGaN, AlGaN, separate/sever/ cleave/ lasing/ etching, substrate, crystal, nuclei/nucleus, seed, orientation, face, orientation, angle, degree, and their boolean combinations were searched.	12/13/08	/sa/

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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